



<b>Substitute for form 1449A/PTO</b> <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				<b>Complete if Known</b>		
				Application Number	09/620,968	
Sheet		1	of	1	Filing Date	July 20, 2000
					First Named Inventor	Shunpei YAMAZAKI
					Art Unit	2814
					Examiner Name	Nathan Ha
					Attorney Docket Number	740756-2183

U.S. PATENT DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code <sup>2</sup> (if known)			
NH		US-4,036,723	07-19-1977	Schwartz et al.	
		US-4,238,312	12-09-1980	Galicki et al.	
		US-4,384,933	05-24-1983	Takasaki	
		US-			
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		US-			

FOREIGN PATENT DOCUMENTS							
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup> Kind Code <sup>2</sup> (if known)				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T <sup>2</sup>

Examiner Signature		Date Considered	4/28/04
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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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Form PTO-1449  
(Rev. 8-83)U S Department of Commerce  
Patent and Trademark Office

Docket 0756-2183

Serial No. 09 620,968

## INFORMATION DISCLOSURE STATEMENT

SEP 09 2002

Applicants: Shunpei YAMAZAKI

Filing Date: July 20, 2000

Group Art Unit: 2818

## FOREIGN PATENT DOCUMENTS

Examiner's Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
M SEP 09 2002 PATENT & TRADEMARK OFFICE	0 046 868	03/10/1982	EP			Full Eng	
	01-119055	05/11/1989	JP			Eng Abst	
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**INFORMATION DISCLOSURE STATEMENT**

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Applicant: Shunpei YAMAZAKI

Filing Date: July 20, 2000

Group: 2811

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
JS	4,849,081	7/18/89	Ross			
JS	3,607,679	9/1971	Melroy et al.			
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	4,804,640	2/1989	Kaganowicz et al.			
JS	4,883,543	11/1989	Gossen, Jr. et al.			

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						Yes	No
JS	26-40078	7/8/90	France				X
JS	02-61128	11/1987	Japan				X
JS	10-96925	12/1967	Great Britain				X

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JS	Young et al., "Correlation... Ta <sub>2</sub> O <sub>5</sub> films", J. Fac. Sci. Technol., Vol. 14, No. 1, Jan/Feb 1977.
	Schrieber et al., J. Electrochem Soc., Vol. 123, No. 1, pp. 30-33 (1976)
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	Jones et al., "Effect of Oxygen on the rf-Sputtering Rate of SiO <sub>2</sub> ", J. Vacuum Sci. and Technology, Vol. 5, No. 3, pp. 84-87.
	Kozuma et al., "Some Properties of Silica Film Made by RF Glow Discharge Sputtering", J. Jap of Appl. Phys., vol. 9, No. 8, August 1970, pp. 983-91.
JS	Suyama et al., Chem. Abstracts 109573w, March 12, 1990, p. 750.

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*Walter M. G.*

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JS	4,951,175	8/1990	Kurosawa et al.			
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JS	Croteau et al. "Growth and Characterisation of PD(Zr, Ti) <sup>03</sup> Films Deposited by Reactive Sputtering of Metallic Targets" Proceedings of the Sixth IEEE International Symposium on Applications of Ferroelectrics, pp. 606-609, 1986.
	definition from Merriam Webster Collegiate Dictionary, Tenth Edition
	IEDM 11-14 Dec. 1988, pp. 222-225, San Francisco, Calif., U.S.; H. Takato et al; "High Performance CMOS Surrounding Gate Transistor (SGT) for Ultra High Density LSIs".
	Mizuno et al., "High Speed and Highly Reliable Trench MOSFET with Dual Gate", Symp. VLSI Tech. Dig. (1988), pp. 23-24.
	Young et al., "Effect of Pulse Duration on the Annealing of Ion Implanted Silicon With a XeC1 Excimer Laser and Solar Cells", Mat. Res. Soc. Symp. Proc., Vol. 13, 1983, pp. 401-406.
JS	Schreiber et al., "High Quality RF-Sputtered Silicon Dioxide Layers", J. Electrochem. Soc., Vol. 123, No. 1, 1976, pp. 30-31.

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Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
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	5,587,340	12/24/96	Yamazaki			
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*Inter. in JA*

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	5,086,010	02/04/92	Kimura			
	5,189,503	2/23/93	Suguro			
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JP 01-171275	7/6/89	Japan			Abstract
JP 62-23117	1/31/87	Japan			Abstract
JP 62-298119	12/25/87	Japan			Abstract
JP 02-47256	2/16/90	Japan			Abstract
JP 03-16129	24/1/91	Japan			Abstract
JP 03-79028	4/4/91	Japan			Abstract
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EP 349187	03/01/90	European			Full
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63-199456	8/17/88	Japan			X
1-248557	10/4/89	Japan			X
2-79475	3/20/90	Japan			X

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						Yes	No
110	JP 59-99726	6/8/84	Japan			Abstract	
	JP 64-82557	03/28/89	Japan			Abstract	
	JP 01-225148	09/08/89	Japan			Abstract	
	JP 04-61337	02/27/92	Japan			Abstract	
	60-005555	01/12/85	Japan			Abstract	
	60-218472	11/01/85	Japan			Abstract	
	61-119045	06/06/86	Japan			Abstract	
	62-056570	03/12/87	Japan			Abstract	
	63-096262	04/27/88	Japan			Abstract	
110	1-218054	08/31/89	Japan			Abstract	

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